nanoFAB Online Sample Submission Procedure

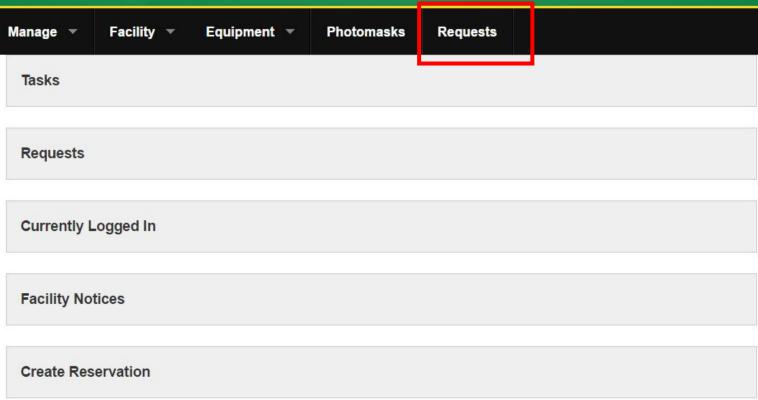
March 2017





ALBERTA

nanoFAB Laboratory Management & Access Control System (LMACS)



- 1. Log onto LMACS
- 2. Click "Requests" button





3. Fill in general information

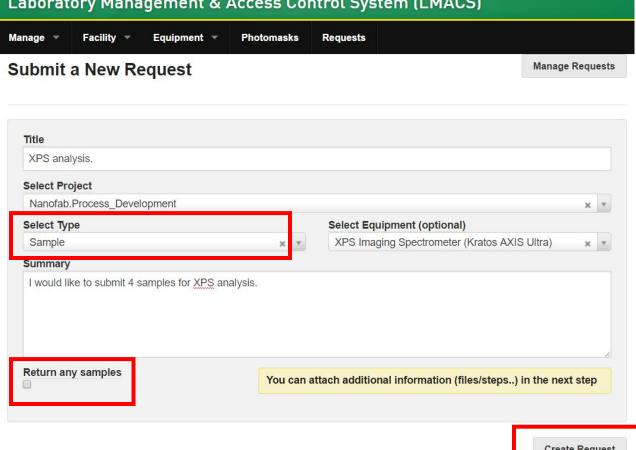
- Select Type "Sample"
- Indicate whether you like samples to be returned or not upon completion of analysis.
- Click "Create Request" button



ONEcard Bear Tracks Email & Apps

nanoFAB

Laboratory Management & Access Control System (LMACS)









4. Click "Edit Request" to add detailed description of samples and analysis.



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Manage ▼ Facility ▼ Equipment ▼ Photomasks Requests

Submit a New Request

Manage Requests

That's it!

You've completed the minimum information required to get started. If you would like to add additional information to your request, you can click the "Edit Request" button. You can also view / edit your other pending requests from the list below.

Pending Requests

14 results

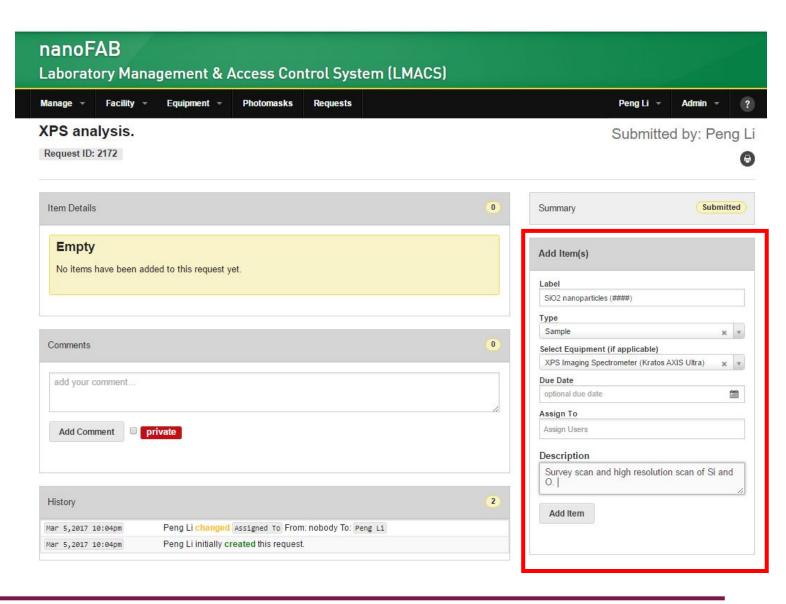
Title	Submitted	Modified	Status
XPS analysis. Sample	Mar 5th	Mar 5th	Submitted





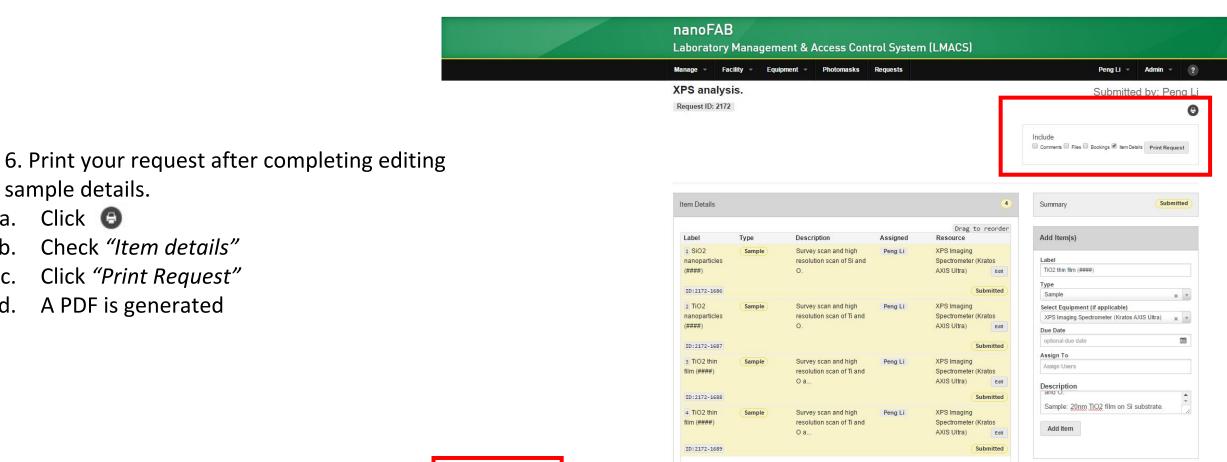
5. Edit sample details in "Add items" session:

- One sample per item
- Sample name in Label
- Select "Sample" type
- Add sample information and analysis details in "description"
- Click "Add Item"













sample details.

Click (3)

Check "Item details"

Click "Print Request"

A PDF is generated



7. Print a hard copy and attach it to your samples

Please include your request ID and Item ID in any related communication with nanoFAB staff members.

XPS analysis.			Request ID: 217			
	ect: Nanofab.Process Development		Submitted By: Peng Li			
Status: Submitted		Submitted Date: Mar 5, 2017				
Type: Sample		Last Modified: Mar 5, 2017				
Priority:		Due Date:				
Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)		Assigned To: Peng Li				
Descripti	on: I would like to submit 4 samples for	XPS analysis.				
Items	(4)					
	ID: 2172-1686: SiO2 nanoparticles	(####) (Sample)	.20			
	Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Status: Submitted	Submitted: Mar 5, 2017			
_	Survey scan and high resolution scan	of Si and O.	W			
	ID: 2172-1687: TiO2 nanoparticles (####) (Sample)					
•	Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Status: Submitted	Submitted: Mar 5, 2017			
	Survey scan and high resolution scan of Ti and O					
	ID: 2172-1688: TiO2 thin film (####) (Sample)					
	Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Status: Submitted	Submitted: Mar 5, 2017			
	Survey scan and high resolution scan	of Ti and O and depth profile m	neasurement of Ti and O.			
_	Sample: 10nm TiO2 film on Si substr	rate.				
	ID: 2172-1689: TiO2 thin film (####) (Sample)					
	Equipment: XPS Imaging Spectrometer (Kratos AXIS Ultra)	Status: Submitted	Submitted: Mar 5, 2017			
	Survey scan and high resolution scan Sample: 20nm TiO2 film on Si substr		neasurement of Ti and O.			





Comments Files Bookings Item Details Print Request

Include

8. Files and Comments:

- Results will be uploaded in the "Files" session after completion of analysis.
- Users can upload related documents here
- Communication is best through "Comments" session.

